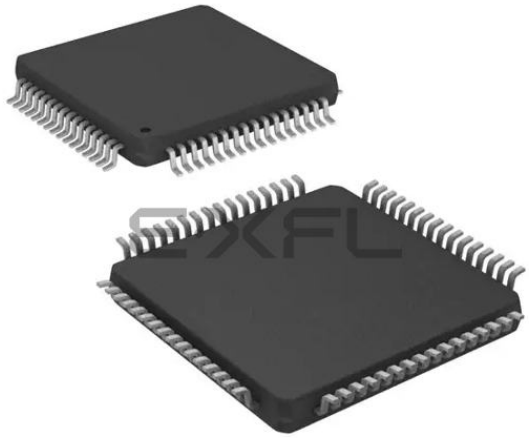


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	50
Program Memory Size	32KB (16K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega32d3-aur

16. TC2 – Timer/Counter Type 2

16.1 Features

- Eight 8-bit timer/counters
  - Four Low-byte timer/counter
  - Four High-byte timer/counter
- Up to eight compare channels in each Timer/Counter 2
  - Four compare channels for the low-byte timer/counter
  - Four compare channels for the high-byte timer/counter
- Waveform generation
  - Single slope pulse width modulation
- Timer underflow interrupts/events
- One compare match interrupt/event per compare channel for the low-byte timer/counter
- Can be used with the event system for count control

16.2 Overview

There are four Timer/Counter 2. These are realized when a Timer/Counter 0 is set in split mode. It is then a system of two eight-bit timer/counters, each with four compare channels. This results in eight configurable pulse width modulation (PWM) channels with individually controlled duty cycles, and is intended for applications that require a high number of PWM channels.

The two eight-bit timer/counters in this system are referred to as the low-byte timer/counter and high-byte timer/counter, respectively. The difference between them is that only the low-byte timer/counter can be used to generate compare match interrupts and events. The two eight-bit timer/counters have a shared clock source and separate period and compare settings. They can be clocked and timed from the peripheral clock, with optional prescaling, or from the event system. The counters are always counting down.

PORTC, PORTD, PORTE, and PORTF each has one Timer/Counter 2. Notation of these are TCC2 (Timer/Counter C2), TCD2, TCE2, and TCF2, respectively.

26. AC – Analog Comparator

26.1 Features

- Two analog comparators (AC)
- Selectable hysteresis
  - No
  - Small
  - Large
- Analog comparator output available on pin
- Flexible input selection
  - All pins on the port
  - Bandgap reference voltage
  - A 64-level programmable voltage scaler of the internal AV_{CC} voltage
- Interrupt and event generation on:
  - Rising edge
  - Falling edge
  - Toggle
- Window function interrupt and event generation on:
  - Signal above window
  - Signal inside window
  - Signal below window
- Constant current source with configurable output pin selection

26.2 Overview

The analog comparator (AC) compares the voltage levels on two inputs and gives a digital output based on this comparison. The analog comparator may be configured to generate interrupt requests and/or events upon several different combinations of input change.

The analog comparator hysteresis can be adjusted in order to achieve the optimal operation for each application.

The input selection includes analog port pins, several internal signals, and a 64-level programmable voltage scaler. The analog comparator output state can also be output on a pin for use by external devices.

A constant current source can be enabled and output on a selectable pin. This can be used to replace, for example, external resistors used to charge capacitors in capacitive touch sensing applications.

The analog comparators are always grouped in pairs on each port. These are called analog comparator 0 (AC0) and analog comparator 1 (AC1). They have identical behavior, but separate control registers. Used as pair, they can be set in window mode to compare a signal to a voltage range instead of a voltage level.

PORTA has one AC pair. Notation is ACA.

Mnemonics	Operands	Description	Operation	Flags	#Clocks
LD	Rd, X+	Load Indirect and Post-Increment	Rd ← (X) X ← X + 1	None	1 (1)(2)
LD	Rd, -X	Load Indirect and Pre-Decrement	X ← X - 1, ← X - 1 Rd ← (X) ← (X)	None	2 (1)(2)
LD	Rd, Y	Load Indirect	Rd ← (Y) ← (Y)	None	1 (1)(2)
LD	Rd, Y+	Load Indirect and Post-Increment	Rd ← (Y) Y ← Y + 1	None	1 (1)(2)
LD	Rd, -Y	Load Indirect and Pre-Decrement	Y ← Y - 1 Rd ← (Y)	None	2 (1)(2)
LDD	Rd, Y+q	Load Indirect with Displacement	Rd ← (Y + q)	None	2 (1)(2)
LD	Rd, Z	Load Indirect	Rd ← (Z)	None	1 (1)(2)
LD	Rd, Z+	Load Indirect and Post-Increment	Rd ← (Z), Z ← Z+1	None	1 (1)(2)
LD	Rd, -Z	Load Indirect and Pre-Decrement	Z ← Z - 1, Rd ← (Z)	None	2 (1)(2)
LDD	Rd, Z+q	Load Indirect with Displacement	Rd ← (Z + q)	None	2 (1)(2)
STS	k, Rr	Store Direct to Data Space	(k) ← Rd	None	2 (1)
ST	X, Rr	Store Indirect	(X) ← Rr	None	1 (1)
ST	X+, Rr	Store Indirect and Post-Increment	(X) ← Rr, X ← X + 1	None	1 (1)
ST	-X, Rr	Store Indirect and Pre-Decrement	X ← X - 1, (X) ← Rr	None	2 (1)
ST	Y, Rr	Store Indirect	(Y) ← Rr	None	1 (1)
ST	Y+, Rr	Store Indirect and Post-Increment	(Y) ← Rr, Y ← Y + 1	None	1 (1)
ST	-Y, Rr	Store Indirect and Pre-Decrement	Y ← Y - 1, (Y) ← Rr	None	2 (1)
STD	Y+q, Rr	Store Indirect with Displacement	(Y + q) ← Rr	None	2 (1)
ST	Z, Rr	Store Indirect	(Z) ← Rr	None	1 (1)
ST	Z+, Rr	Store Indirect and Post-Increment	(Z) ← Rr Z ← Z + 1	None	1 (1)
ST	-Z, Rr	Store Indirect and Pre-Decrement	Z ← Z - 1	None	2 (1)
STD	Z+q, Rr	Store Indirect with Displacement	(Z + q) ← Rr	None	2 (1)
LPM		Load Program Memory	R0 ← (Z)	None	3
LPM	Rd, Z	Load Program Memory	Rd ← (Z)	None	3
LPM	Rd, Z+	Load Program Memory and Post-Increment	Rd ← (Z), Z ← Z + 1	None	3
ELPM		Extended Load Program Memory	R0 ← (RAMPZ:Z)	None	3
ELPM	Rd, Z	Extended Load Program Memory	Rd ← (RAMPZ:Z)	None	3
ELPM	Rd, Z+	Extended Load Program Memory and Post-Increment	Rd ← (RAMPZ:Z), Z ← Z + 1	None	3
SPM		Store Program Memory	(RAMPZ:Z) ← R1:R0	None	-
SPM	Z+	Store Program Memory and Post-Increment by 2	(RAMPZ:Z) ← R1:R0, Z ← Z + 2	None	-
IN	Rd, A	In From I/O Location	Rd ← I/O(A)	None	1
OUT	A, Rr	Out To I/O Location	I/O(A) ← Rr	None	1
PUSH	Rr	Push Register on Stack	STACK ← Rr	None	1 (1)
POP	Rd	Pop Register from Stack	Rd ← STACK	None	2 (1)

Table 32-11. Gain Stage Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
R_{in}	Input resistance	Switched in normal mode		4.0		kΩ
C_{sample}	Input capacitance	Switched in normal mode		4.4		pF
	Signal range	Gain stage output	0		AV_{CC} - 0.6	V
	Propagation delay	ADC conversion rate	1/2	1	3	Clk_{ADC} cycles
	Clock frequency	Same as ADC	100		1800	kHz
	Gain error	0.5× gain, normal mode		-1		%
		1× gain, normal mode		-1		
		8× gain, normal mode		-1		
		64× gain, normal mode		5		
	Offset error, input referred	0.5× gain, normal mode		10		mV
		1× gain, normal mode		5		
		8× gain, normal mode		-20		
		64× gain, normal mode		-126		

32.1.7 Analog Comparator Characteristics

Table 32-12. Analog Comparator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{off}	Input offset voltage			10		mV
I_{lk}	Input leakage current			<10	50	nA
	Input voltage range		-0.1		AV_{CC}	V
	AC startup time			50		µs
V_{hys1}	Hysteresis, none	V_{CC} = 1.6V - 3.6V		0		mV
V_{hys2}	Hysteresis, small	V_{CC} = 1.6V - 3.6V		15		
V_{hys3}	Hysteresis, large	V_{CC} = 1.6V - 3.6V		30		
t_{delay}	Propagation delay	V_{CC} = 3.0V, T = 85°C		20	40	ns
		V_{CC} = 3.0V		17		
	64-level voltage scaler	Integral non-linearity (INL)		0.3	0.5	lsb
	Current source accuracy after calibration			5		%
	Current source calibration range	Single mode	4		6	µA

Table 32-54. External Clock with Prescaler [1] for System Clock

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$1/t_{CK}$	Clock Frequency [2]	V_{CC} = 1.6 - 1.8V	0		90	MHz
		V_{CC} = 2.7 - 3.6V	0		142	
t_{CK}	Clock Period	V_{CC} = 1.6 - 1.8V	11			ns
		V_{CC} = 2.7 - 3.6V	7			
t_{CH}	Clock High Time	V_{CC} = 1.6 - 1.8V	4.5			
		V_{CC} = 2.7 - 3.6V	2.4			
t_{CL}	Clock Low Time	V_{CC} = 1.6 - 1.8V	4.5			
		V_{CC} = 2.7 - 3.6V	2.4			
t_{CR}	Rise Time (for maximum frequency)	V_{CC} = 1.6 - 1.8V			1.5	
		V_{CC} = 2.7 - 3.6V			1.0	
t_{CF}	Fall Time (for maximum frequency)	V_{CC} = 1.6 - 1.8V			1.5	
		V_{CC} = 2.7 - 3.6V			1.0	
Δt_{CK}	Change in period from one clock cycle to the next				10	%

Notes:
1. System Clock Prescalers must be set so that maximum CPU clock frequency for device is not exceeded.
2. The maximum frequency vs. supply voltage is linear between 1.6V and 2.7V, and the same applies for all other parameters with supply voltage conditions.

32.2.13.7 External 16MHz Crystal Oscillator and XOSC Characteristics

Table 32-55. External 16MHz Crystal Oscillator and XOSC Characteristics

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
	Cycle to cycle jitter	XOSCPWR=0	FRQRANGE=0		0		ns
			FRQRANGE=1, 2, or 3		0		
		XOSCPWR=1			0		
	Long term jitter	XOSCPWR=0	FRQRANGE=0		0		
			FRQRANGE=1, 2, or 3		0		
		XOSCPWR=1			0		
	Frequency error	XOSCPWR=0	FRQRANGE=0		0.03		%
			FRQRANGE=1		0.03		
			FRQRANGE=2 or 3		0.03		
		XOSCPWR=1			0.003		
	Duty cycle	XOSCPWR=0	FRQRANGE=0		50		
			FRQRANGE=1		50		
			FRQRANGE=2 or 3		50		
		XOSCPWR=1			50		

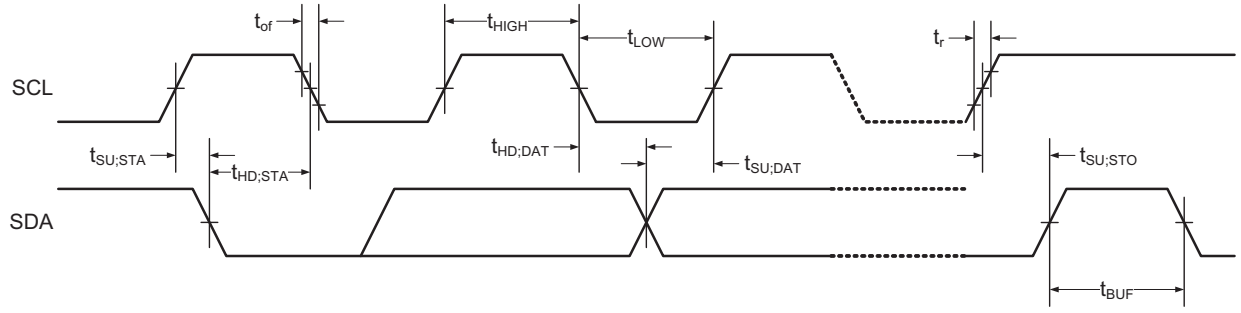
Table 32-57. SPI Timing Characteristics and Requirements

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{SCK}	SCK period	Master		(See Table 20-3 in XMEGA D manual)		ns
t_{SCKW}	SCK high/low width	Master		0.5 * SCK		
t_{SCKR}	SCK rise time	Master		2.7		
t_{SCKF}	SCK fall time	Master		2.7		
t_{MIS}	MISO setup to SCK	Master		10		
t_{MIH}	MISO hold after SCK	Master		10		
t_{MOS}	MOSI setup SCK	Master		0.5 * SCK		
t_{MOH}	MOSI hold after SCK	Master		1		
t_{SSCK}	Slave SCK Period	Slave	4 * t Clk_{PER}			
t_{SSCKW}	SCK high/low width	Slave	2 * t Clk_{PER}			
t_{SSCKR}	SCK rise time	Slave			1600	
t_{SSCKF}	SCK fall time	Slave			1600	
t_{SIS}	MOSI setup to SCK	Slave	3			
t_{SIH}	MOSI hold after SCK	Slave	t Clk_{PER}			
t_{SSS}	$\overline{SS}$ setup to SCK	Slave	21			
t_{SSH}	$\overline{SS}$ hold after SCK	Slave	20			
t_{SOS}	MISO setup SCK	Slave		8		
t_{SOH}	MISO hold after SCK	Slave		13		
t_{SOSS}	MISO setup after $\overline{SS}$ low	Slave		11		
t_{SOSH}	MISO hold after $\overline{SS}$ high	Slave		8		

32.2.15 Two-wire Interface Characteristics

Table 32-58 on page 100 describes the requirements for devices connected to the two-wire interface bus. The Atmel AVR XMEGA two-wire interface meets or exceeds these requirements under the noted conditions. Timing symbols refer to Figure 32-14.

Figure 32-14.Two-wire Interface Bus Timing



32.3.5 I/O Pin Characteristics

The I/O pins compiles with the JEDEC LVTTL and LVCMOS specification and the high- and low level input and output voltage limits or exceeds this specification.

Table 32-65. I/O Pin Characteristics

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{OH} (1)/ I_{OL} (2)	I/O pin source/sink current			-15		15	mA
V_{IH}	High level input voltage	V_{CC} = 2.4 - 3.6V		0.7 * V_{CC}		V_{CC} + 0.5	V
		V_{CC} = 1.6 - 2.4V		0.8 * V_{CC}		V_{CC} + 0.5	
V_{IL}	Low level input voltage	V_{CC} = 2.4 - 3.6V		-0.5		0.3 * V_{CC}	
		V_{CC} = 1.6 - 2.4V		-0.5		0.2 * V_{CC}	
V_{OH}	High level output voltage	V_{CC} = 3.3V	I_{OH} = -4mA	2.6	2.9		
		V_{CC} = 3.0V	I_{OH} = -3mA	2.1	2.6		
		V_{CC} = 1.8V	I_{OH} = -1mA	1.4	1.6		
V_{OL}	Low level output voltage	V_{CC} = 3.3V	I_{OL} = 8mA		0.4	0.76	
		V_{CC} = 3.0V	I_{OL} = 5mA		0.3	0.64	
		V_{CC} = 1.8V	I_{OL} = 3mA		0.2	0.46	
I_{IN}	Input leakage current I/O pin	T = 25°C			<0.01	1.0	µA
R_P	Pull/buss keeper resistor				25		kΩ

Notes:
1. The sum of all I_{OH} for PORTA and PORTB must not exceed 100mA.
   The sum of all I_{OH} for PORTC, PORTD, and PORTE must for each port not exceed 200mA.
   The sum of all I_{OH} for pins PF[0-5] on PORTF must not exceed 200mA.
   The sum of all I_{OL} for pins PF[6-7] on PORTF, PORTR, and PDI must not exceed 100mA.
2. The sum of all I_{OL} for PORTA and PORTB must not exceed 100mA.
   The sum of all I_{OL} for PORTC, PORTD, and PORTE must for each port not exceed 200mA.
   The sum of all I_{OL} for pins PF[0-5] on PORTF must not exceed 200mA.
   The sum of all I_{OL} for pins PF[6-7] on PORTF, PORTR, and PDI must not exceed 100mA.

32.3.6 ADC Characteristics

Table 32-66. Power Supply, Reference, and Input Range

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
AV_{CC}	Analog supply voltage		V_{CC} - 0.3		V_{CC} + 0.3	V
V_{REF}	Reference voltage		1		AV_{CC} - 0.6	
R_{in}	Input resistance	Switched			4.5	kΩ
C_{in}	Input capacitance	Switched			5	pF
R_{AREF}	Reference input resistance	(leakage only)		>10		MΩ
C_{AREF}	Reference input capacitance	Static load		7		pF
V_{in}	Input range		0		V_{REF}	V
	Conversion range	Differential mode, Vinp - Vinn	$-V_{REF}$		V_{REF}	
	Conversion range	Single ended unsigned mode, Vinp	-ΔV		V_{REF} - ΔV	
ΔV	Fixed offset voltage			200		lsb

Table 32-67. Clock and Timing

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk_{ADC}	ADC clock frequency	Maximum is 1/4 of peripheral clock frequency	100		1800	kHz
		Measuring internal signals	100		125	
f_{ClkADC}	Sample rate		16		300	ksps
f_{ADC}	Sample rate	Current limitation (CURRLIMIT) off	16		300	ksps
		CURRLIMIT = LOW	16		250	
		CURRLIMIT = MEDIUM	16		150	
		CURRLIMIT = HIGH	16		50	
	Sampling time	1/2 Clk_{ADC} cycle	0.28		320	µs
	Conversion time (latency)	(RES+2)/2 + GAIN RES (Resolution) = 8 or 12, GAIN = 0 to 3	5.5		10	Clk_{ADC} cycles
	Start-up time	ADC clock cycles		12	24	
	ADC settling time	After changing reference or input mode		7	7	

32.3.8 Bandgap and Internal 1.0V Reference Characteristics

Table 32-71. Bandgap and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC		1 Clk_{PER} + 2.5µs		µs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.99	1.0	1.01	
	Variation over voltage and temperature	Calibrated at T = 85°C		1		%

32.3.9 Brownout Detection Characteristics

Table 32-72. Brownout Detection Characteristics (1)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.40	1.60	1.70	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

32.3.10 External Reset Characteristics

Table 32-73. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width		1000	100		ns
V_{RST}	Reset threshold voltage	V_{CC} = 2.7 - 3.6V		0.45 * V_{CC}		V
		V_{CC} = 1.6 - 2.7V		0.45 * V_{CC}		
R_{RST}	Reset pin pull-up resistor			27		kΩ

Table 32-155. Accuracy Characteristics

Symbol	Parameter	Condition [1]		Min.	Typ.	Max.	Units
RES	Resolution	12-bit resolution	Differential	8	12	12	Bits
			Single ended signed	7	11	11	
			Single ended unsigned	8	12	12	
INL [2]	Integral non-linearity	Differential mode	16ksps, V_{REF} = 3V		0.5	1	lsb
			16ksps, all V_{REF}		0.8	2	
			300ksps, V_{REF} = 3V		0.6	1	
			300ksps, all V_{REF}		1	2	
		Single ended unsigned mode	16ksps, V_{REF} = 3.0V		0.5	1	
			16ksps, all V_{REF}		1.3	2	
DNL [2]	Differential non-linearity	Differential mode	16ksps, V_{REF} = 3V		0.3	1	
			16ksps, all V_{REF}		0.5	1	
			300ksps, V_{REF} = 3V		0.35	1	
			300ksps, all V_{REF}		0.5	1	
		Single ended unsigned mode	16ksps, V_{REF} = 3.0V		0.6	1	
			16ksps, all V_{REF}		0.6	1	
	Offset error	Differential mode	300ksps, V_{REF} = 3V		-7		mV
			Temperature drift, V_{REF} = 3V		0.01		mV/K
			Operating voltage drift		0.16		mV/V
	Gain error	Differential mode	External reference		-5		mV
			AV_{CC}/1.6		-5		
			AV_{CC}/2.0		-6		
			Bandgap		±10		
			Temperature drift		0.02		mV/K
			Operating voltage drift		2		mV/V
	Gain error	Single ended unsigned mode	External reference		-8		mV
			AV_{CC}/1.6		-8		
			AV_{CC}/2.0		-8		
			Bandgap		±10		
			Temperature drift		0.03		mV/K
			Operating voltage drift		2		mV/V

Notes:
1. Unless otherwise noted all linearity, offset and gain error numbers are valid under the condition that external V_{REF} is used.
2. Maximum numbers are based on characterisation and not tested in production, and valid for 5% to 95% input voltage range.

Figure 33-74. Active Mode Supply Current vs. V_{CC}

f_{SYS} = 32.768kHz internal oscillator

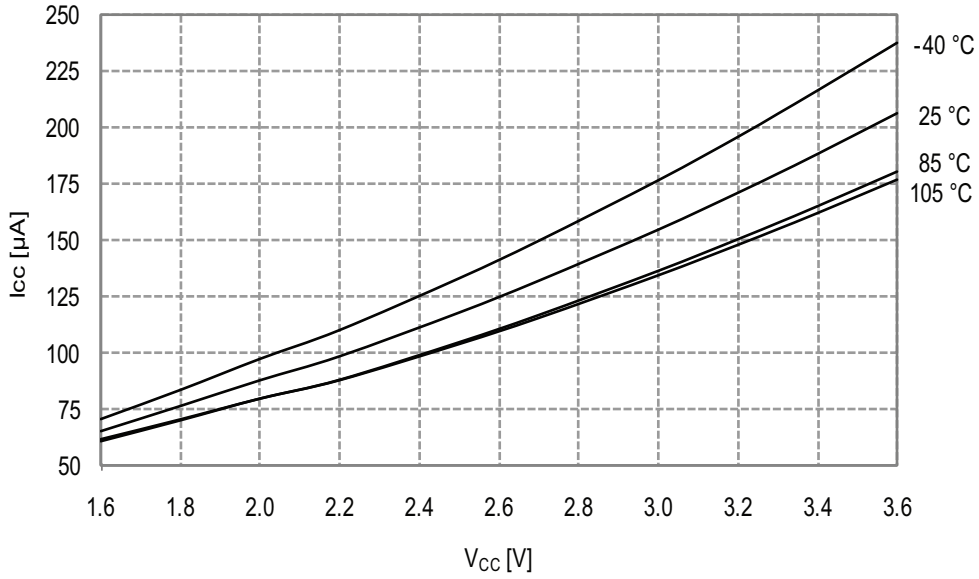


Figure 33-75. Active Mode Supply Current vs. V_{CC}

f_{SYS} = 1MHz external clock

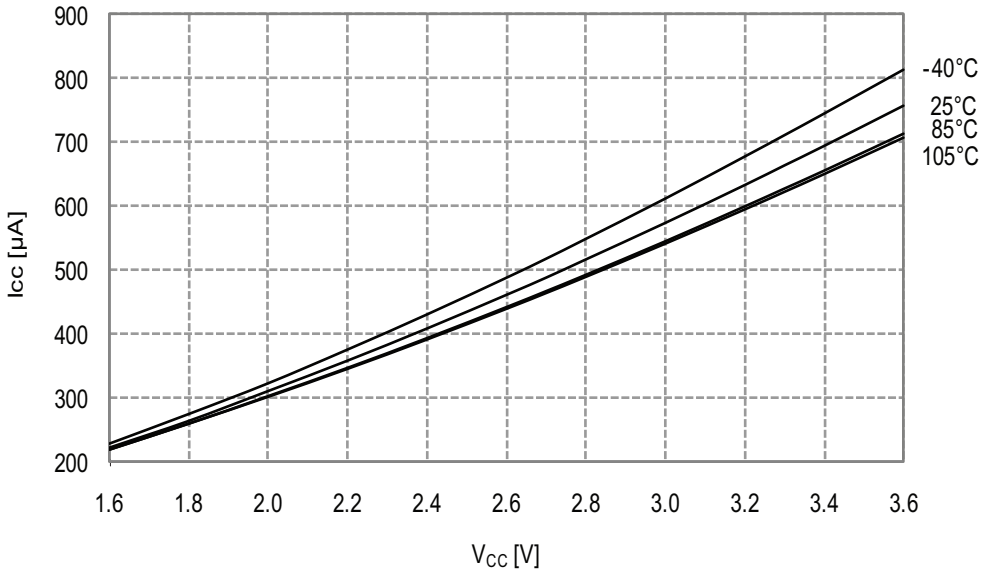


Figure 33-110. Offset Error vs. V_{REF}

T = 25°C, V_{CC} = 3.6V, ADC sample rate = 300ksps

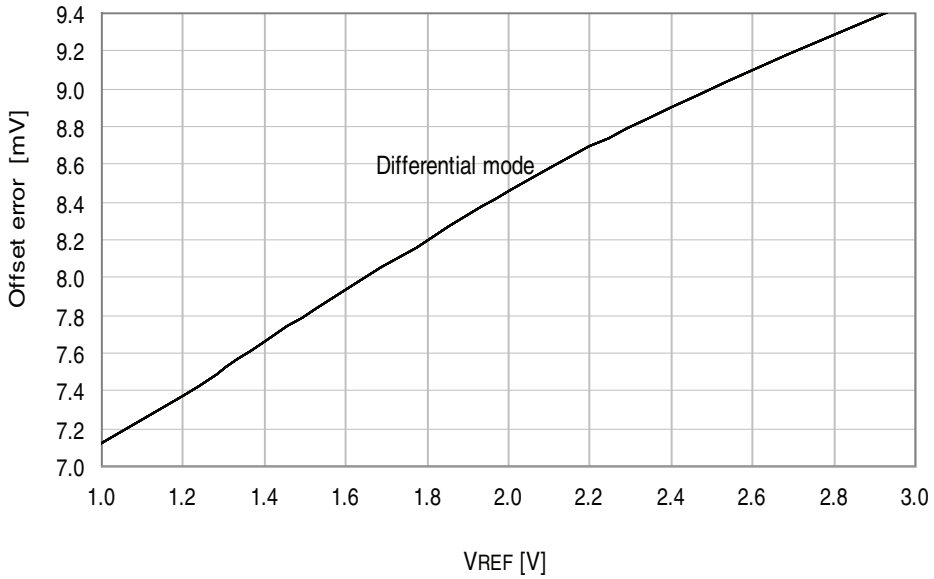
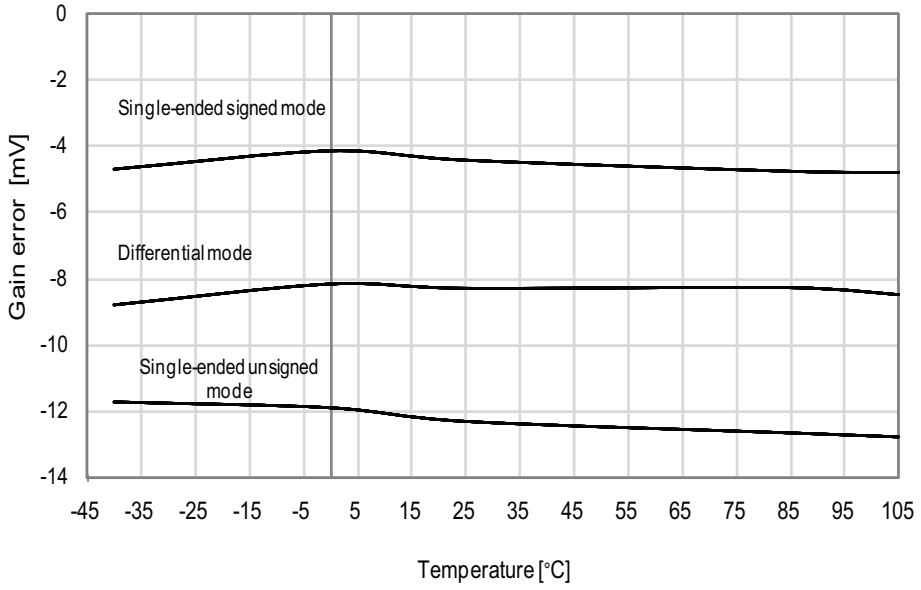


Figure 33-111. Gain Error vs. Temperature

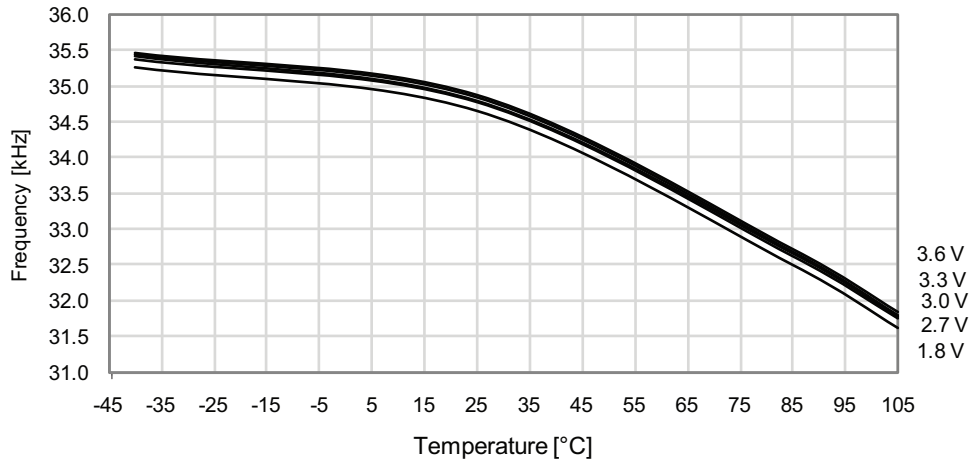
V_{CC} = 3.0V, V_{REF} = external 2.0V



33.3.8 Oscillator Characteristics

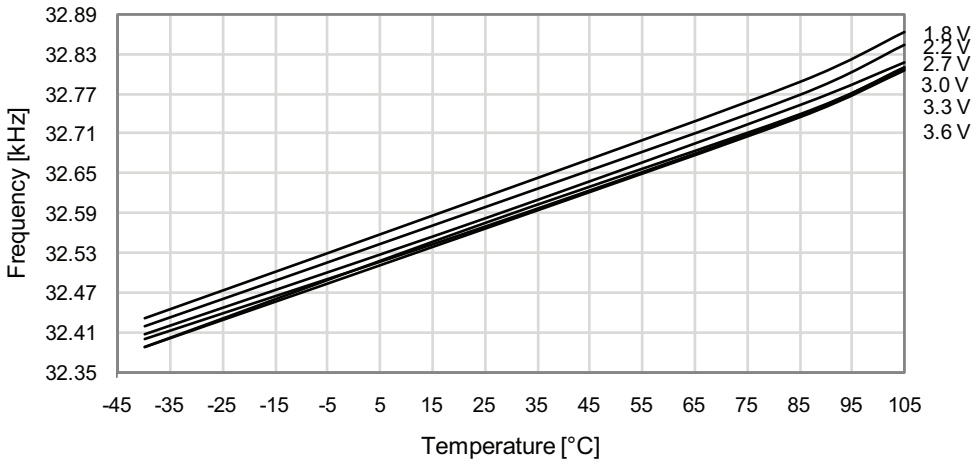
33.3.8.1 Ultra Low-Power Internal Oscillator

Figure 33-195. Ultra Low-Power Internal Oscillator Frequency vs. Temperature



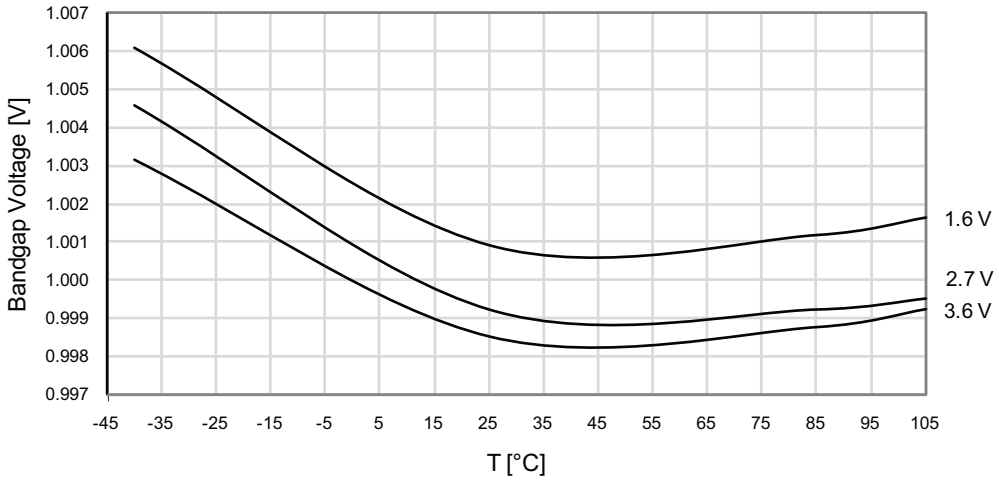
33.3.8.2 32.768kHz Internal Oscillator

Figure 33-196. 32.768kHz Internal Oscillator Frequency vs. Temperature



33.4.5 Internal 1.0V Reference Characteristics

Figure 33-257.ADC Internal 1.0V Reference vs. Temperature



33.4.6 BOD Characteristics

Figure 33-258.BOD Thresholds vs. Temperature

BOD level = 1.6V

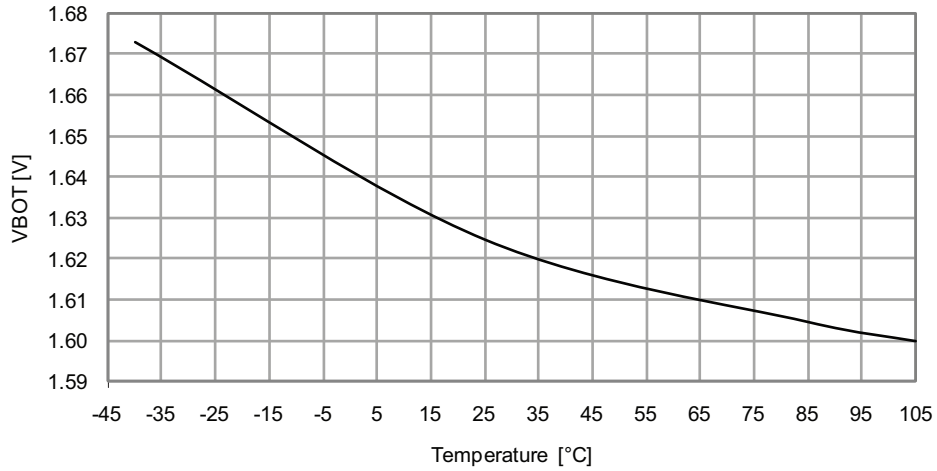


Figure 33-383. INL Error vs. Sample Rate

T = 25°C, V_{CC} = 3.6V, V_{REF} = 3.0V external

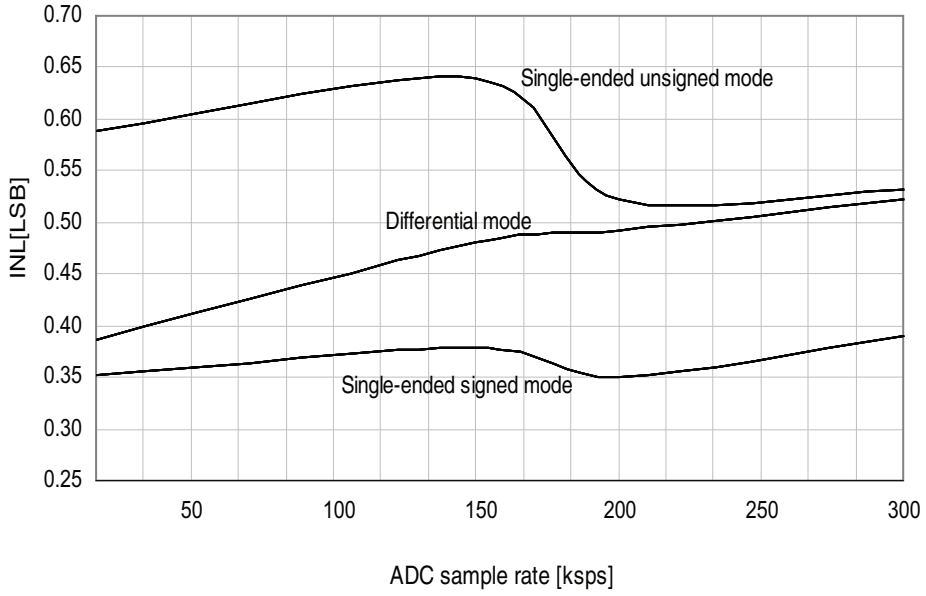
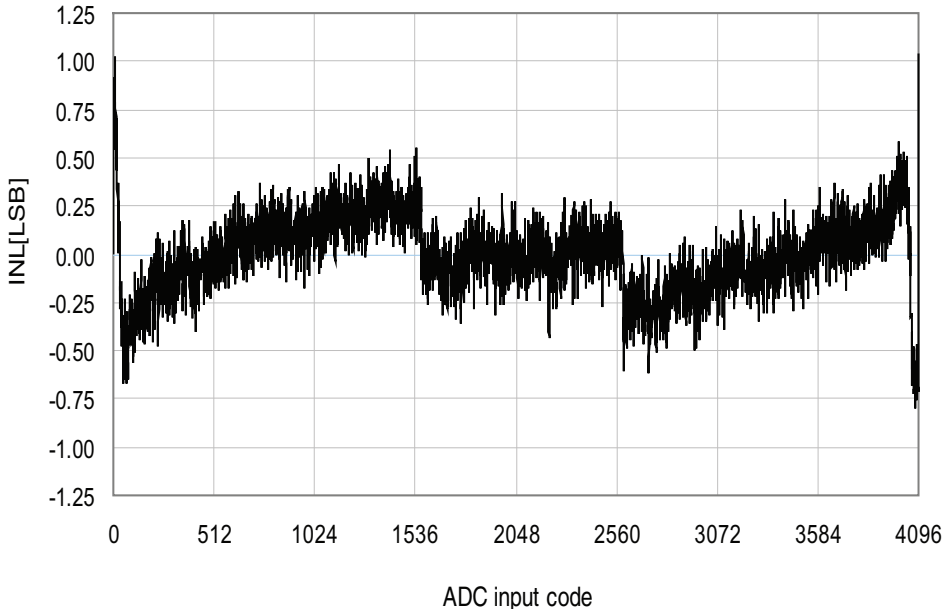


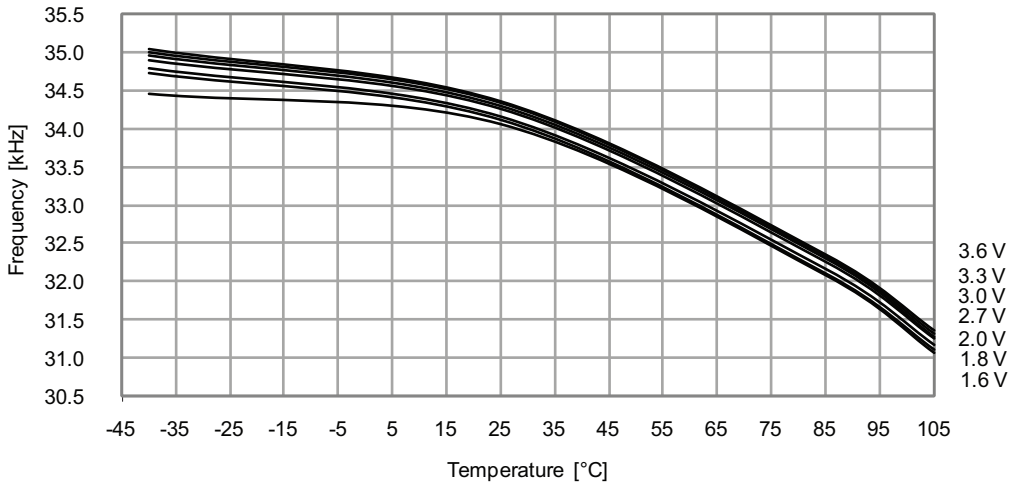
Figure 33-384. INL Error vs. Input Code



33.6.8 Oscillator Characteristics

33.6.8.1 Ultra Low-Power Internal Oscillator

Figure 33-405. Ultra Low-Power Internal Oscillator Frequency vs. Temperature



33.6.8.2 32.768kHz Internal Oscillator

Figure 33-406. 32.768kHz Internal Oscillator Frequency vs. Temperature

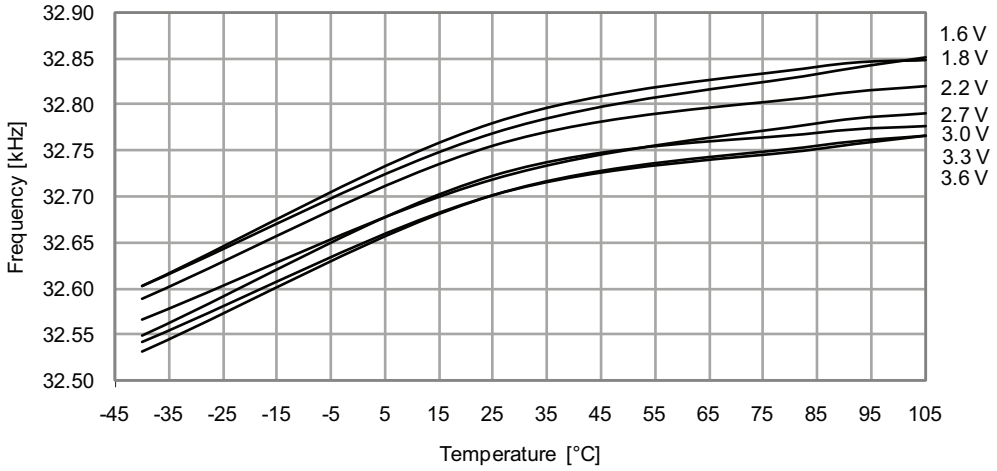


Figure 33-413. 32MHz Internal Oscillator CALA Calibration Step Size

V_{CC} = 3.0V

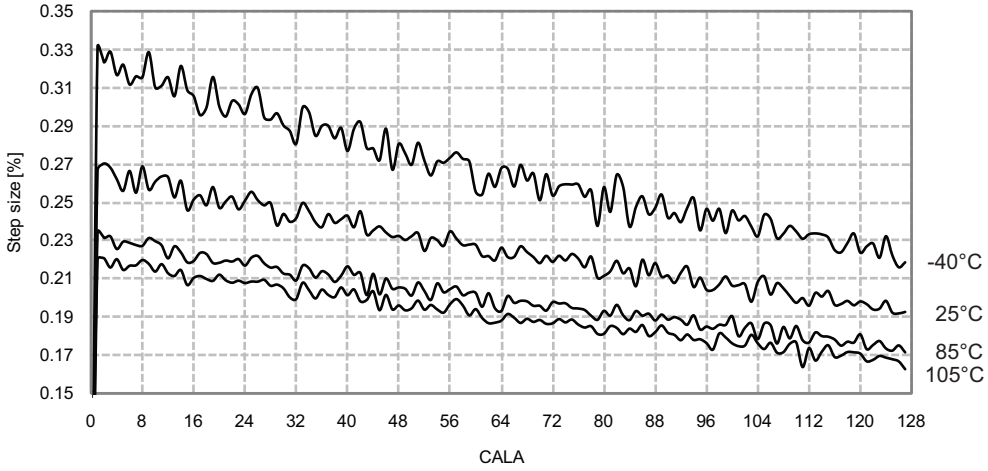
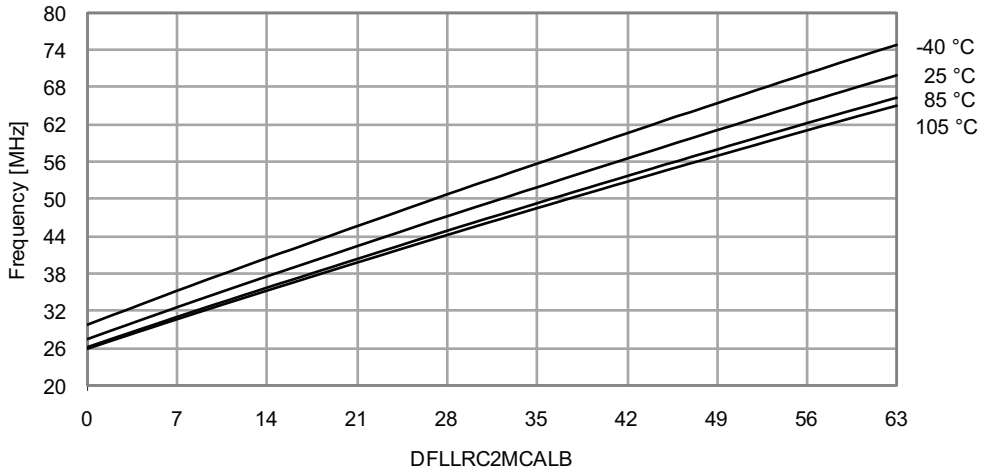


Figure 33-414. 32MHz Internal Oscillator Frequency vs. CALB Calibration Value

V_{CC} = 3.0V



16. NMI Flag for Crystal Oscillator Failure automatically cleared

NMI flag for Crystal Oscillator Failure (XOSCFDIF) will be automatically cleared when executing the NMI interrupt handler.

Problem fix/workaround

This device revision has only one NMI interrupt source, so checking the interrupt source in software is not required.

17. RTC Counter value not correctly read after sleep

If the RTC is set to wake up the device on RTC Overflow and bit 0 of RTC CNT is identical to bit 0 of RTC PER as the device is entering sleep, the value in the RTC count register can not be read correctly within the first prescaled RTC clock cycle after wake-up. The value read will be the same as the value in the register when entering sleep.

The same applies if RTC Compare Match is used as wake-up source.

Problem fix/workaround

Wait at least one prescaled RTC clock cycle before reading the RTC CNT value.

18. Pending asynchronous RTC-interrupts will not wake up device

Asynchronous Interrupts from the Real-Time-Counter that is pending when the sleep instruction is executed, will be ignored until the device is woken from another source or the source triggers again.

Problem fix/workaround

None.

19. TWI Transmit collision flag not cleared on repeated start

The TWI transmit collision flag should be automatically cleared on start and repeated start, but is only cleared on start.

Problem fix/workaround

Clear the flag in software after address interrupt.

20. Clearing TWI Stop Interrupt Flag may lock the bus

If software clears the STOP Interrupt Flag (APIF) on the same Peripheral Clock cycle as the hardware sets this flag due to a new address received, CLKHOLD is not cleared and the SCL line is not released. This will lock the bus.

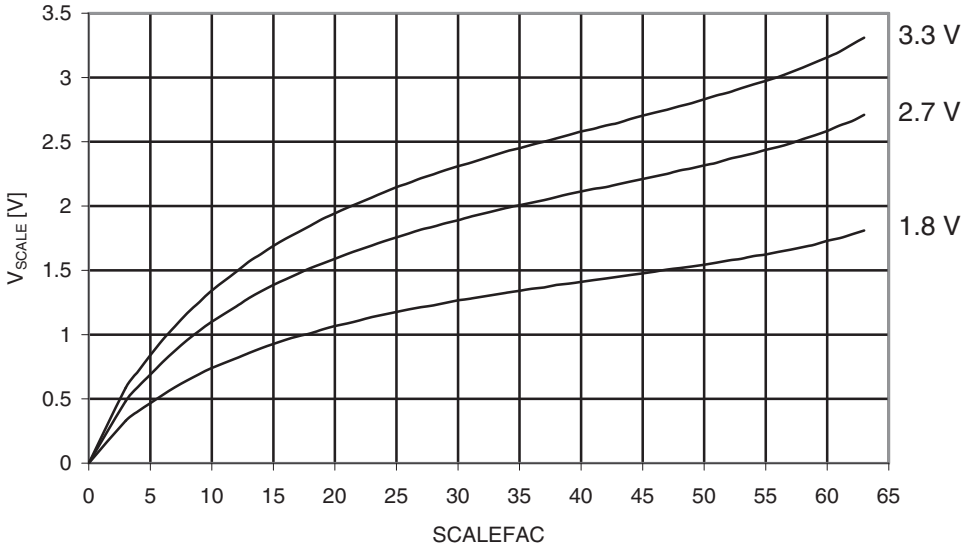
Problem fix/workaround

Check if the bus state is IDLE. If this is the case, it is safe to clear APIF. If the bus state is not IDLE, wait for the SCL pin to be low before clearing APIF.

Code:

```
/* Only clear the interrupt flag if within a "safe zone". */
while ( /* Bus not IDLE: */
       ((COMMS_TWI.MASTER.STATUS & TWI_MASTER_BUSSTATE_gm) !=
         TWI_MASTER_BUSSTATE_IDLE_gc)) &&
         /* SCL not held by slave: */
         !(COMMS_TWI.SLAVE.STATUS & TWI_SLAVE_CLKHOLD_bm)
      )
{
    /* Ensure that the SCL line is low */
```

Figure 34-3. Analog Comparator Voltage Scaler vs. Scalefac
T = 25°C



Problem fix/workaround

Use external voltage input for the analog comparator if accurate voltage levels are needed.

3. ADC gain stage cannot be used for single conversion

The ADC gain stage will not output correct result for single conversion that is triggered and started from software or event system.

Problem fix/workaround

When the gain stage is used, the ADC must be set in free running mode for correct results.

4. ADC has increased INL error for some operating conditions

Some ADC configurations or operating condition will result in increased INL error.

In signed mode INL is increased to:

6LSB for sample rates above 130ksps, and up to 8LSB for 200ksps sample rate.

6LSB for reference voltage below 1.1V when V_{CC} is above 3.0V.

20LSB for ambient temperature below 0°C and reference voltage below 1.3V.

In unsigned mode, the INL error cannot be guaranteed, and this mode should not be used.

Problem fix/workaround

None, avoid using the ADC in the above configurations in order to prevent increased INL error. Use the ADC in signed mode also for single ended measurements.

5. ADC gain stage output range is limited to 2.4V

The amplified output of the ADC gain stage will never go above 2.4V, hence the differential input will only give correct output when below 2.4V/gain. For the available gain settings, this gives a differential input range of:

Problem fix/workaround

Table 34-6. Configure PWM and CWCM According to this Table:

PGM	CWCM	Description
0	0	PGM and CWCM disabled
0	1	PGM enabled
1	0	PGM and CWCM enabled
1	1	PGM enabled

11. PWM is not restarted properly after a fault in cycle-by-cycle mode

When the AWeX fault restore mode is set to cycle-by-cycle, the waveform output will not return to normal operation at first update after fault condition is no longer present.

Problem fix/workaround

Do a write to any AWeX I/O register to re-enable the output.

12. BOD will be enabled after any reset

If any reset source goes active, the BOD will be enabled and keep the device in reset if the V_{CC} voltage is below the programmed BOD level. During Power-On Reset, reset will not be released until V_{CC} is above the programmed BOD level even if the BOD is disabled.

Problem fix/workaround

Do not set the BOD level higher than V_{CC} even if the BOD is not used.

13. EEPROM page buffer always written when NVM DATA0 is written

If the EEPROM is memory mapped, writing to NVM DATA0 will corrupt data in the EEPROM page buffer.

Problem fix/workaround

Before writing to NVM DATA0, for example when doing software CRC or flash page buffer write, check if EEPROM page buffer active loading flag (EELOAD) is set. Do not write NVM DATA0 when EELOAD is set.

14. Pending full asynchronous pin change interrupts will not wake the device

Any full asynchronous pin-change Interrupt from pin 2, on any port, that is pending when the sleep instruction is executed, will be ignored until the device is woken from another source or the source triggers again. This applies when entering all sleep modes where the System Clock is stopped.

Problem fix/workaround

None.

15. Pin configuration does not affect Analog Comparator output

The Output/Pull and inverted pin configuration does not affect the Analog Comparator output.

Problem fix/workaround

None for Output/Pull configuration.

For inverted I/O, configure the Analog Comparator to give an inverted result (that is, connect positive input to the negative AC input and vice versa), or use and external inverter to change polarity of Analog Comparator output.